

**Notice of References Cited**

Application/Control No.

09/730,508

Applicant(s)/Patent Under  
Reexamination  
YAN ET AL.

Examiner

Christina Ildebrando

Art Unit

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0132724	09-2002	Labarge et al.	502/64
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 0 848 984	06-1998	EPO	Mizuno et al.	----
	O					
	P					
	Q					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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